

TOSHIBA CMOS DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

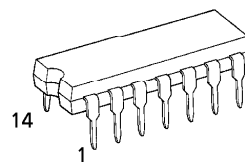
TC4030BP, TC4030BF, TC4030BFN

TC4030B QUAD EXCLUSIVE-OR GATE

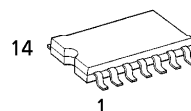
TC4030B contains four circuits of exclusive OR gates. Since the buffers of two stage inverters are provided for all the outputs, the input/output voltage characteristic has been improved and the noise immunity has been also improved. And increase of transmission time due to load capacity increase is kept minimum.

Wide variety of applicaitons are offered, such as digital comparators and parity circuits.

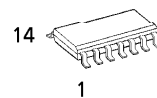
(Note) The JEDEC SOP (FN) is not available in Japan.



P (DIP14-P-300-2.54)
Weight : 0.96g (Typ.)



F (SOP14-P-300-1.27)
Weight : 0.18g (Typ.)



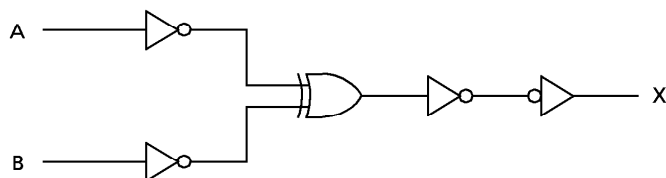
FN (SOL14-P-150-1.27)
Weight : 0.12g (Typ.)

MAXIMUM RATINGS

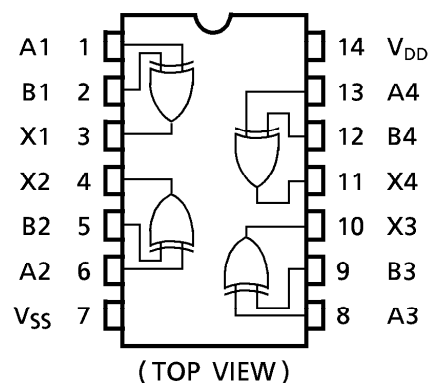
CHARACTERISTIC	SYMBOL	RATING	UNIT
DC Supply Voltage	V_{DD}	$V_{SS} - 0.5 \sim V_{SS} + 20$	V
Input Voltage	V_{IN}	$V_{SS} - 0.5 \sim V_{DD} + 0.5$	V
Output Voltage	V_{OUT}	$V_{SS} - 0.5 \sim V_{DD} + 0.5$	V
DC Input Current	I_{IN}	± 10	mA
Power Dissipation	P_D	300 (DIP) / 180 (SOIC)	mW
Operating Temperature Range	T_{opr}	$-40 \sim 85$	$^{\circ}\text{C}$
Storage Temperature Range	T_{stg}	$-65 \sim 150$	$^{\circ}\text{C}$

CIRCUIT DIAGRAM

1/4 TC4030B



PIN ASSIGNMENT



TRUTH TABLE

INPUTS		OUTPUT
A	B	X
L	L	L
L	H	H
H	L	H
H	H	L

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● TOSHIBA is continually working to improve the quality and the reliability of its products. Nevertheless, semiconductor devices in general can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to observe standards of safety, and to avoid situations in which a malfunction or failure of a TOSHIBA product could cause loss of human life, bodily injury or damage to property. In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent products specifications. Also, please keep in mind the precautions and conditions set forth in the TOSHIBA Semiconductor Reliability Handbook.

RECOMMENDED OPERATING CONDITIONS ($V_{SS} = 0V$)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
DC Supply Voltage	V_{DD}		3	—	18	V
Input Voltage	V_{IN}		0	—	V_{DD}	V

STATIC ELECTRICAL CHARACTERISTICS ($V_{SS} = 0V$)

CHARACTERISTIC	SYM-BOL	TEST CONDITION	V_{DD} (V)	- 40°C		25°C			85°C		UNIT
				MIN.	MAX.	MIN.	TYP.	MAX.	MIN.	MAX.	
High-Level Output Voltage	V_{OH}	$ I_{OUT} < 1\mu A$ $V_{IN} = V_{SS}, V_{DD}$	5	4.95	—	4.95	5.00	—	4.95	—	V
			10	9.95	—	9.95	10.00	—	9.95	—	
			15	14.95	—	14.95	15.00	—	14.95	—	
Low-Level Output Voltage	V_{OL}	$ I_{OUT} < 1\mu A$ $V_{IN} = V_{SS}, V_{DD}$	5	—	0.05	—	0.00	0.05	—	0.05	V
			10	—	0.05	—	0.00	0.05	—	0.05	
			15	—	0.05	—	0.00	0.05	—	0.05	
Output High Current	I_{OH}	$V_{OH} = 4.6V$	5	- 0.61	—	- 0.51	- 1.0	—	- 0.42	—	mA
		$V_{OH} = 2.5V$	5	- 2.50	—	- 2.10	- 4.0	—	- 1.70	—	
		$V_{OH} = 9.5V$	10	- 1.50	—	- 1.30	- 2.2	—	- 1.10	—	
		$V_{OH} = 13.5V$	15	- 4.00	—	- 3.40	- 9.0	—	- 2.80	—	
		$V_{IN} = V_{SS}, V_{DD}$									
Output Low Current	I_{OL}	$V_{OL} = 0.4V$	5	0.61	—	0.51	1.2	—	0.42	—	mA
		$V_{OL} = 0.5V$	10	1.50	—	1.30	3.2	—	1.10	—	
		$V_{OL} = 1.5V$	15	4.00	—	3.40	12.0	—	2.80	—	
		$V_{IN} = V_{SS}, V_{DD}$									
Input High Voltage	V_{IH}	$V_{OUT} = 0.5V, 4.5V$	5	3.5	—	3.5	2.75	—	3.5	—	V
		$V_{OUT} = 1.0V, 9.0V$	10	7.0	—	7.0	5.50	—	7.0	—	
		$V_{OUT} = 1.5V, 13.5V$	15	11.0	—	11.0	8.25	—	11.0	—	
		$ I_{OUT} < 1\mu A$									
Input Low Voltage	V_{IL}	$V_{OUT} = 0.5V, 4.5V$	5	—	1.5	—	2.25	1.5	—	1.5	V
		$V_{OUT} = 1.0V, 9.0V$	10	—	3.0	—	4.50	3.0	—	3.0	
		$V_{OUT} = 1.5V, 13.5V$	15	—	4.0	—	6.75	4.0	—	4.0	
		$ I_{OUT} < 1\mu A$									
Input Current	"H" Level	I_{IH}	$V_{IH} = 18V$	18	—	0.1	—	10^{-5}	0.1	—	μA
	"L" Level	I_{IL}	$V_{IL} = 0V$	18	—	- 0.1	—	$- 10^{-5}$	- 0.1	—	
Quiescent Supply Current	I_{DD}	$V_{IN} = V_{SS}, V_{DD}^*$	5	—	1	—	0.001	1	—	7.5	μA
			10	—	2	—	0.001	2	—	15.0	
			15	—	4	—	0.002	4	—	30.0	

* All valid input combinations.

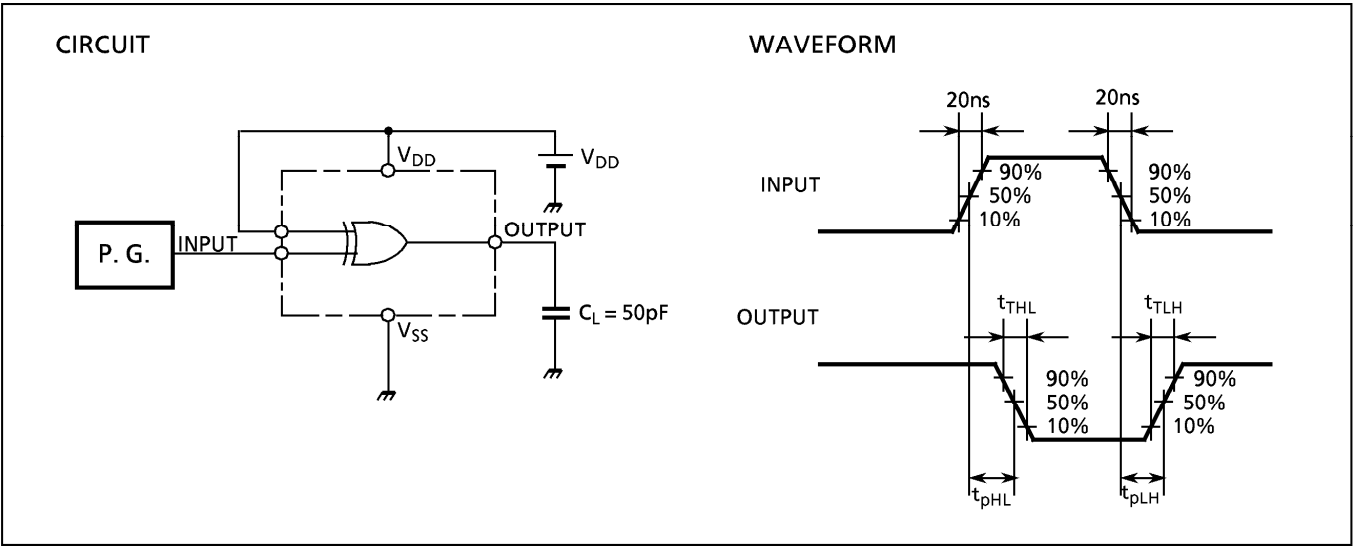
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DYNAMIC ELECTRICAL CHARACTERISTICS (Ta = 25°C, Vss = 0V, CL = 50pF)

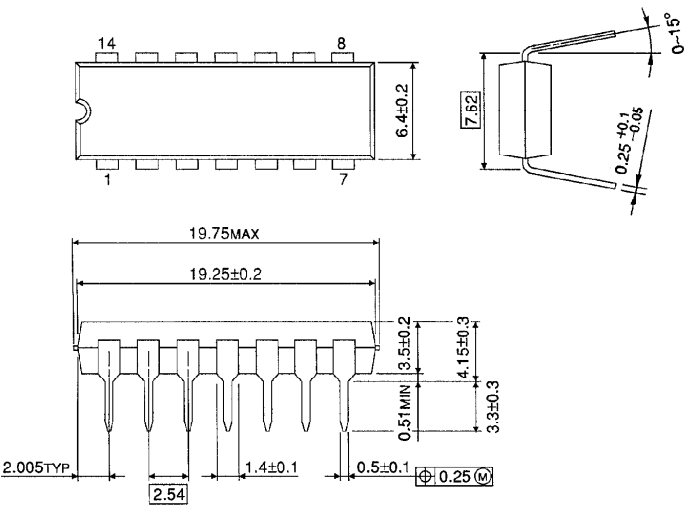
CHARACTERISTIC	SYMBOL	TEST CONDITION	VDD(V)	MIN.	TYP.	MAX.	UNIT
Output Transition Time (Low to High)	tTLH		5	—	70	200	ns
			10	—	35	100	
			15	—	30	80	
Output Transition Time (High to Low)	tTHL		5	—	70	200	ns
			10	—	35	100	
			15	—	30	80	
Propagation Delay Time	tPLH tPHL		5	—	90	280	ns
			10	—	45	130	
			15	—	35	100	
Input Capacitance	CIN			—	5	7.5	pF

CIRCUIT AND WAVEFORM FOR MEASUREMENT OF DYNAMIC CHARACTERISTICS



DIP 14PIN OUTLINE DRAWING (DIP14-P-300-2.54)

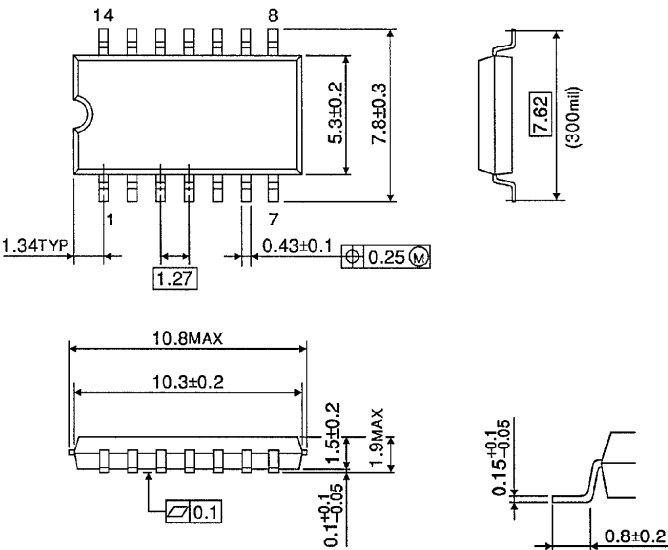
Unit in mm



Weight : 0.96g (Typ.)

SOP 14PIN (200mil BODY) OUTLINE DRAWING (SOP14-P-300-1.27)

Unit in mm

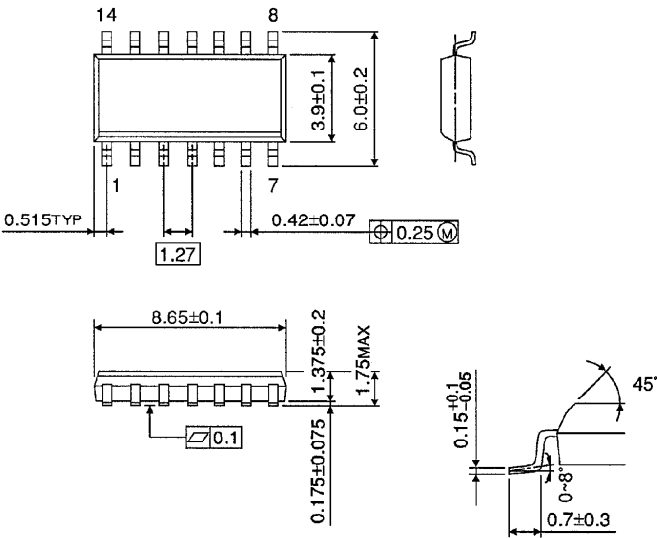


Weight : 0.18g (Typ.)

SOP 14PIN (150mil BODY) OUTLINE DRAWING (SOL14-P-150-1.27)

Unit in mm

(Note) This package is not available in Japan.



Weight : 0.12g (Typ.)